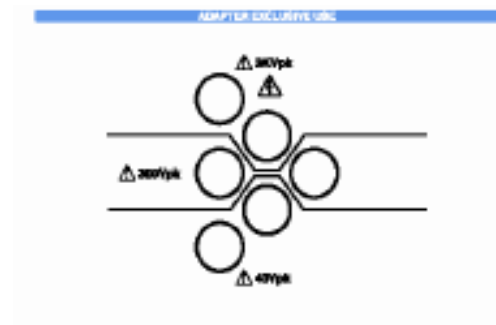
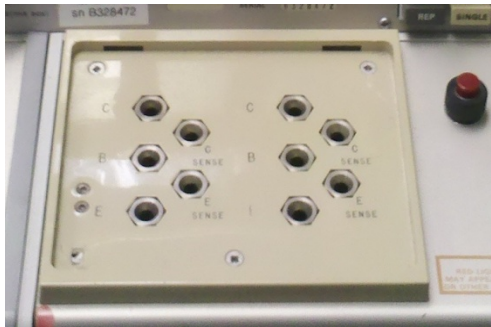


# Comparison with Tektronix

1

Same pin assignment

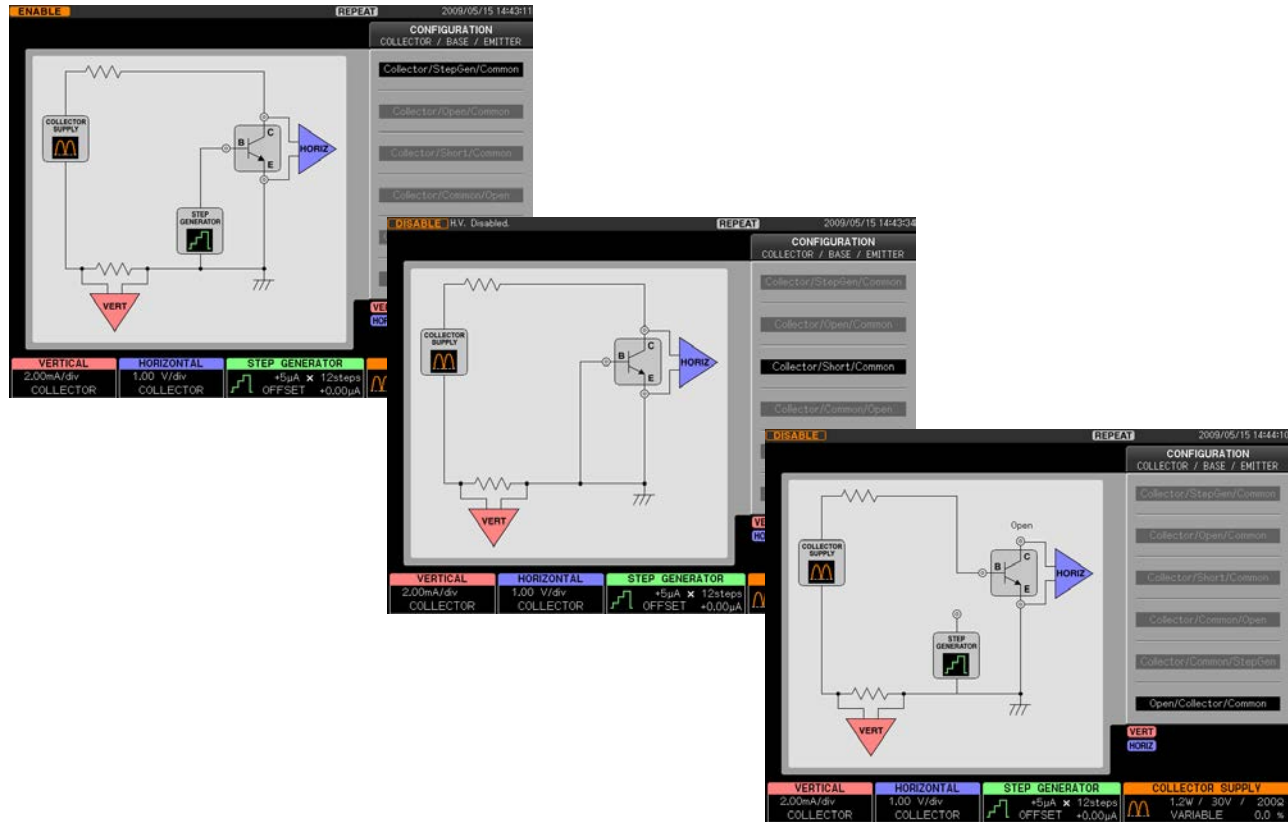


Customer can use their own Tektronix Adaptors

# Comparison with Tektronix

2

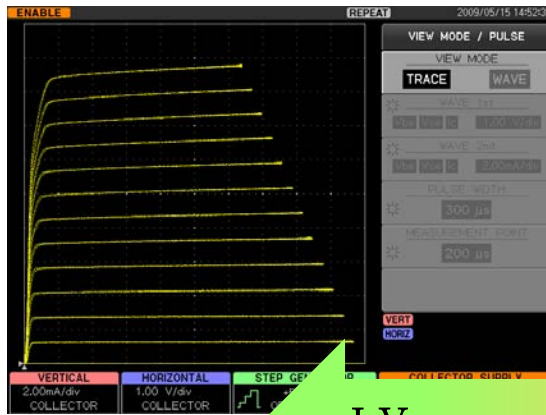
## Graphical configuration display



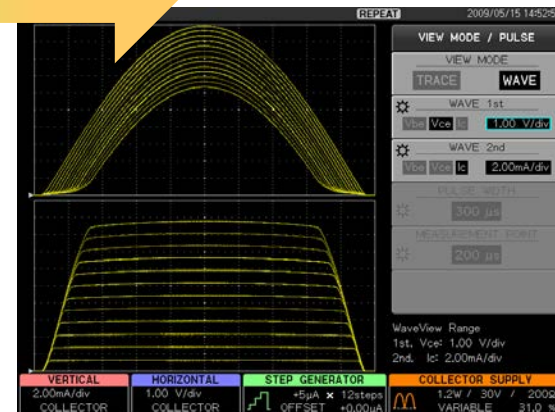
# Comparison with Tektronix

3

## TRACE & WAVE, Two of the VIEW mode



I-V curve I-t/V-t curve

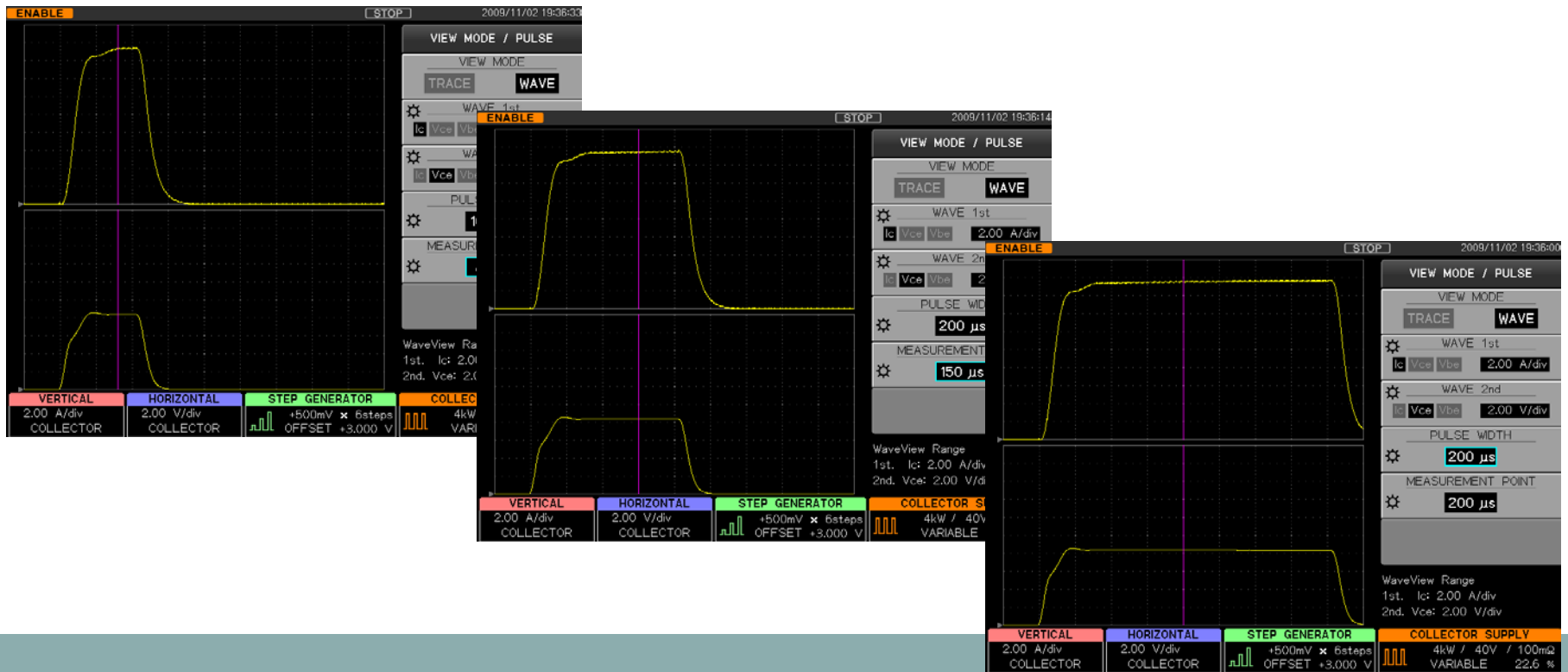


# Comparison with Tektronix

4

## High Current mode

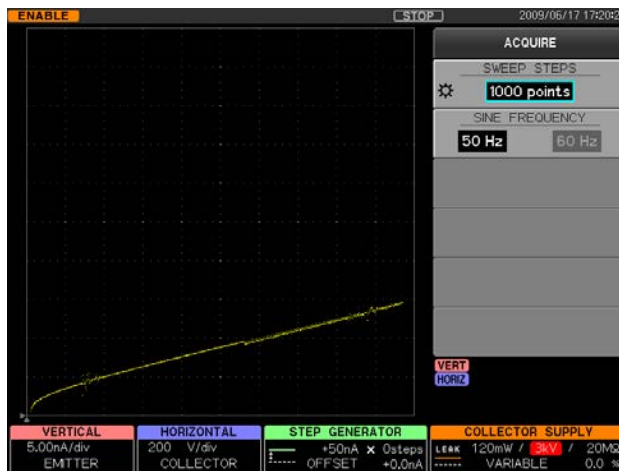
- Variable **Output pulse width**: 50us to 400us
- Selection of **measurement point**: Available
- Variable **repetition frequency**: 80ms to 1000ms



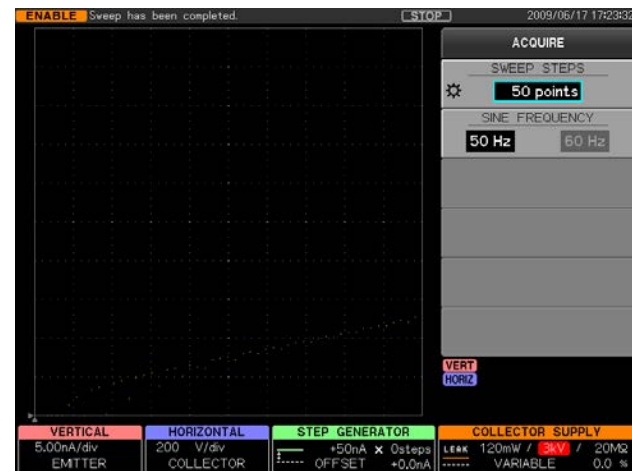
# Comparison with Tektronix

5

Max. numbers of acquisition data can be specified at the SWEEP



**SWEEP at 1000point**



**SWEEP at 50points**

- 20 to 1000 points can be specified

**Detailed measurement can be done**

**“Improvement in efficiency”**

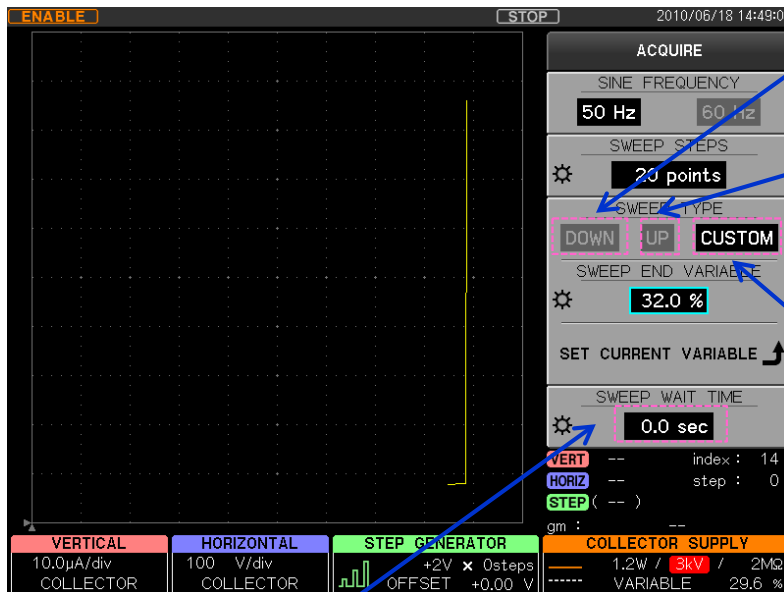
# Comparison with Tektronix

6

## Useful SWEEP function

- **SWEEP TYPE**: selectable from UP, DOWN, CUSTOM
- **SWEEP WATE**: waiting time to measurement can be specified

### Example of CUSTOM setting



Downward SWEEP

Upward SWEEP

SWEEP in between two specified value

Wait time from changing the voltage setting to the measurement can be Specified at the SWEEP.



LEAKAGE measurements can be started after having stable condition on device

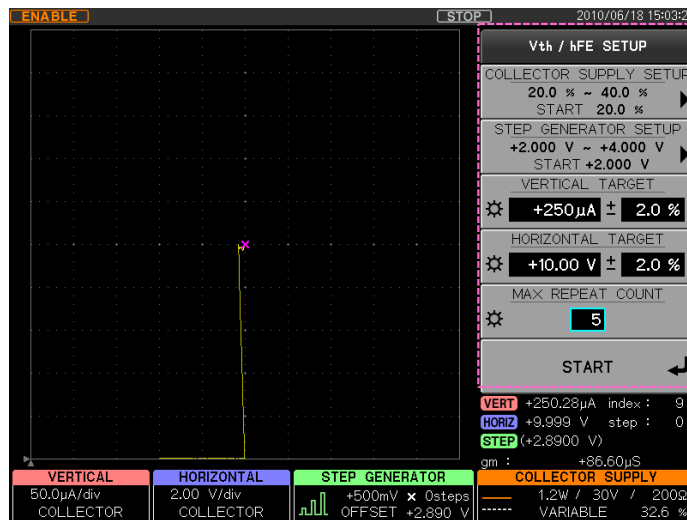
# Comparison with Tektronix

7

## CS-800 Semiconductor Parameter Search

■ **Built-in option program** for automatic  $V_{th}$  measurement

Example of MOSFET  $V_{th}$  measurement



### V<sub>th</sub>/hFE SETUP

Automatic  $V_{th}$ , hFE measurement can be performed



Automatic measurement can contribute improvement of measurement efficiency